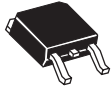




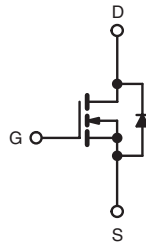
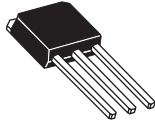
Power MOSFET

| PRODUCT SUMMARY | |
|----------------------------|----------------------------|
| V _{DS} (V) | 400 |
| R _{DS(on)} (Ω) | V _{GS} = 10 V 3.6 |
| Q _g (Max.) (nC) | 12 |
| Q _{gs} (nC) | 1.9 |
| Q _{gd} (nC) | 6.5 |
| Configuration | Single |

DPAK (TO-252)



IPAK (TO-251)



N-Channel MOSFET

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Surface Mount (IRFR310/SiHFR310)
- Straight Lead (IRFU310/SiHFU310)
- Available in Tape and Reel
- Fast Switching
- Fully Avalanche Rated
- Lead (Pb)-free Available



Available
RoHS*
COMPLIANT

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The DPAK is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU/SiHFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 W are possible in typical surface mount applications.

| ORDERING INFORMATION | | | | | |
|----------------------|---------------|----------------------------|---------------------------|----------------------------|---------------|
| Package | DPAK (TO-252) | DPAK (TO-252) | DPAK (TO-252) | DPAK (TO-252) | IPAK (TO-251) |
| Lead (Pb)-free | IRFR310PbF | IRFR310TRLPbF ^a | IRFR310TRPbF ^a | IRFR310TRRPbF ^a | IRFU310PbF |
| | SiHFR310-E3 | SiHFR310TL-E3 ^a | SiHFR310T-E3 ^a | SiHFR310TR-E3 ^a | SiHFU310-E3 |
| SnPb | IRFR310 | IRFR310TRL ^a | IRFR310TR ^a | - | IRFU310 |
| | SiHFR310 | SiHFR310TL ^a | SiHFR310T ^a | - | SiHFU310 |

Note

a. See device orientation.

| ABSOLUTE MAXIMUM RATINGS T _C = 25 °C, unless otherwise noted | | | |
|---|-----------------------------------|-------------------------|------|
| PARAMETER | SYMBOL | LIMIT | UNIT |
| Drain-Source Voltage | V _{DS} | 400 | V |
| Gate-Source Voltage | V _{GS} | ± 20 | |
| Continuous Drain Current | V _{GS} at 10 V | T _C = 25 °C | A |
| | | T _C = 100 °C | |
| Pulsed Drain Current ^a | I _{DM} | 6.0 | W/°C |
| Linear Derating Factor | | 0.20 | |
| Linear Derating Factor (PCB Mount) ^e | | 0.020 | |
| Single Pulse Avalanche Energy ^b | E _{AS} | 86 | mJ |
| Repetitive Avalanche Current ^a | I _{AR} | 1.7 | A |
| Repetitive Avalanche Energy ^a | E _{AR} | 2.5 | mJ |
| Maximum Power Dissipation | P _D | T _C = 25 °C | W |
| | | T _A = 25 °C | |
| Peak Diode Recovery dV/dt ^c | dV/dt | 4.0 | V/ns |
| Operating Junction and Storage Temperature Range | T _J , T _{stg} | - 55 to + 150 | °C |
| Soldering Recommendations (Peak Temperature) | for 10 s | 260 ^d | |

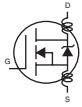

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- V_{DD} = 50 V, starting T_J = 25 °C, L = 52 mH, R_G = 25 Ω, I_{AS} = 1.7 A (see fig. 12).
- I_{SD} ≤ 1.7 A, di/dt ≤ 40 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.
- 1.6 mm from case.
- When mounted on 1" square PCB (FR-4 or G-10 material).

| THERMAL RESISTANCE RATINGS | | | | |
|--|------------|------|------|------|
| PARAMETER | SYMBOL | TYP. | MAX. | UNIT |
| Maximum Junction-to-Ambient (PCB Mounted, steady-state) ^a | R_{thJA} | - | 50 | °C/W |
| Maximum Junction-to-Ambient | R_{thJA} | - | 110 | |
| Maximum Junction-to-Case | R_{thJC} | - | 5.0 | |

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

| SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted | | | | | | | |
|--|---------------------|--|---|------|------|----------------------|---------------|
| PARAMETER | SYMBOL | TEST CONDITIONS | | MIN. | TYP. | MAX. UNIT | |
| Static | | | | | | | |
| Drain-Source Breakdown Voltage | V_{DS} | $V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$ | | 400 | - | - V | |
| V_{DS} Temperature Coefficient | $\Delta V_{DS}/T_J$ | Reference to $25\text{ }^\circ\text{C}$, $I_D = 1\text{ mA}$ | | - | 0.47 | - $V/^\circ\text{C}$ | |
| Gate-Source Threshold Voltage | $V_{GS(th)}$ | $V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$ | | 2.0 | - | 4.0 V | |
| Gate-Source Leakage | I_{GSS} | $V_{GS} = \pm 20\text{ V}$ | | - | - | $\pm 100\text{ nA}$ | |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS} = 400\text{ V}, V_{GS} = 0\text{ V}$ | | - | - | 25 μA | |
| | | $V_{DS} = 320\text{ V}, V_{GS} = 0\text{ V}, T_J = 125\text{ }^\circ\text{C}$ | | - | - | 250 μA | |
| Drain-Source On-State Resistance | $R_{DS(on)}$ | $V_{GS} = 10\text{ V}$ | $I_D = 1.0\text{ A}^b$ | - | - | 3.6 Ω | |
| Forward Transconductance | g_{fs} | $V_{DS} = 50\text{ V}, I_D = 1.0\text{ A}^b$ | | 0.97 | - | - S | |
| Dynamic | | | | | | | |
| Input Capacitance | C_{iss} | $V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}, f = 1.0\text{ MHz}$, see fig. 5 ^c | | - | 170 | - | pF |
| Output Capacitance | C_{oss} | | | - | 34 | - | |
| Reverse Transfer Capacitance | C_{rss} | | | - | 6.3 | - | |
| Total Gate Charge | Q_g | $V_{GS} = 10\text{ V}$ | $I_D = 2.0\text{ A}, V_{DS} = 320\text{ V}$, see fig. 6 and 13 ^{b, c} | - | - | 12 | nC |
| Gate-Source Charge | Q_{gs} | | | - | - | 1.9 | |
| Gate-Drain Charge | Q_{gd} | | | - | - | 6.5 | |
| Turn-On Delay Time | $t_{d(on)}$ | $V_{DD} = 200\text{ V}, I_D = 2.0\text{ A}, R_G = 24\text{ }\Omega, R_D = 95\text{ }\Omega$, see fig. 10 ^{b, c} | | - | 7.9 | - | ns |
| Rise Time | t_r | | | - | 9.9 | - | |
| Turn-Off Delay Time | $t_{d(off)}$ | | | - | 21 | - | |
| Fall Time | t_f | | | - | 11 | - | |
| Internal Drain Inductance | L_D | Between lead, 6 mm (0.25") from package and center of die contact  | | - | 4.5 | - | nH |
| Internal Source Inductance | L_S | | | - | 7.5 | - | |
| Drain-Source Body Diode Characteristics | | | | | | | |
| Continuous Source-Drain Diode Current | I_S | MOSFET symbol showing the integral reverse p - n junction diode  | | - | - | 1.7 | A |
| Pulsed Diode Forward Current ^a | I_{SM} | | | - | - | 6.0 | |
| Body Diode Voltage | V_{SD} | $T_J = 25\text{ }^\circ\text{C}, I_S = 1.7\text{ A}, V_{GS} = 0\text{ V}^b$ | | - | - | 1.6 | V |
| Body Diode Reverse Recovery Time | t_{rr} | $T_J = 25\text{ }^\circ\text{C}, I_F = 2.0\text{ A}, dI/dt = 100\text{ A}/\mu\text{s}^b$ | | - | 240 | 540 | ns |
| Body Diode Reverse Recovery Charge | Q_{rr} | | | - | 0.85 | 1.6 | μC |
| Forward Turn-On Time | t_{on} | Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D) | | | | | |

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
 b. Pulse width $\leq 300\text{ }\mu\text{s}$; duty cycle $\leq 2\%$.



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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

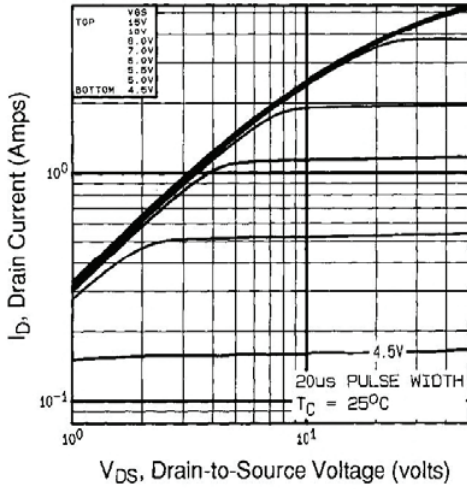


Fig. 1 - Typical Output Characteristics, $T_C = 25\text{ }^\circ\text{C}$

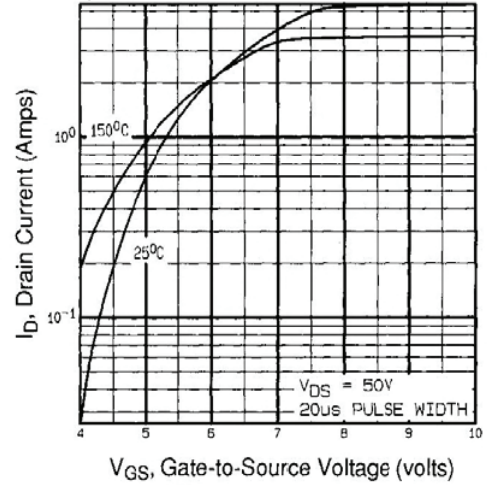


Fig. 3 - Typical Transfer Characteristics

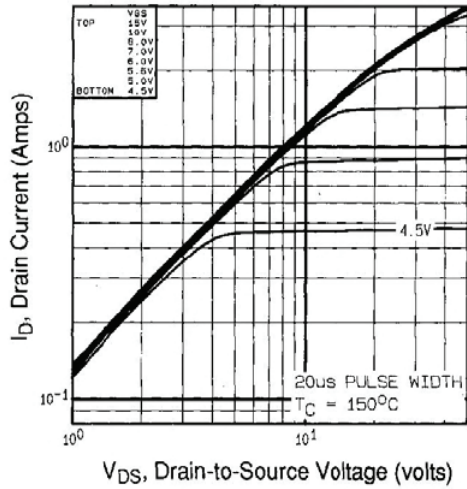


Fig. 2 - Typical Output Characteristics, $T_C = 150\text{ }^\circ\text{C}$

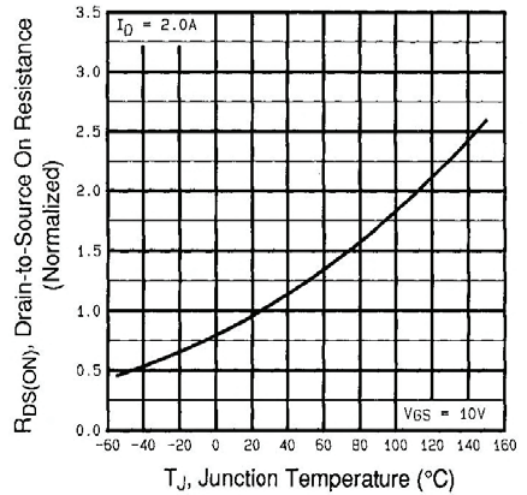


Fig. 4 - Normalized On-Resistance vs. Temperature



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IRFR310, IRFU310, SiHFR310, SiHFU310

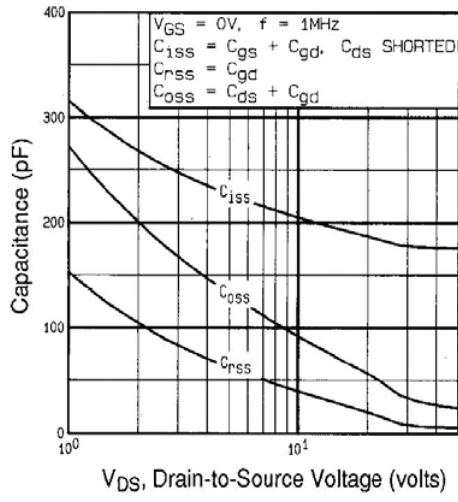


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

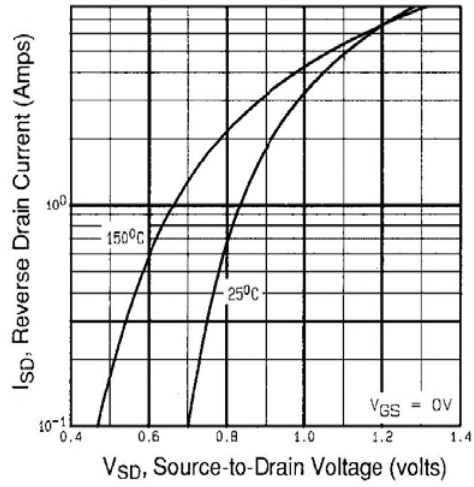


Fig. 7 - Typical Source-Drain Diode Forward Voltage

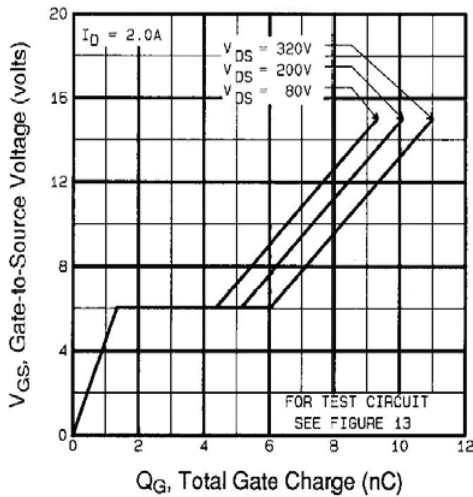


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

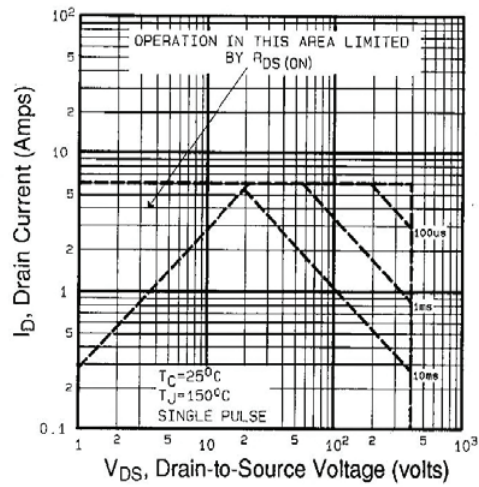


Fig. 8 - Maximum Safe Operating Area



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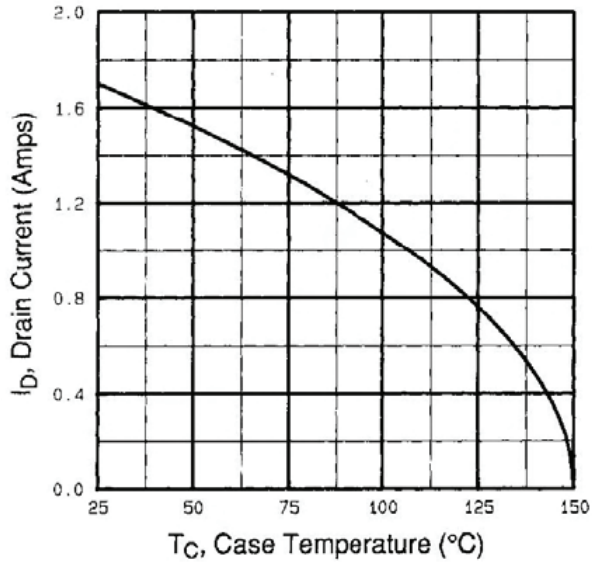


Fig. 9 - Maximum Drain Current vs. Case Temperature

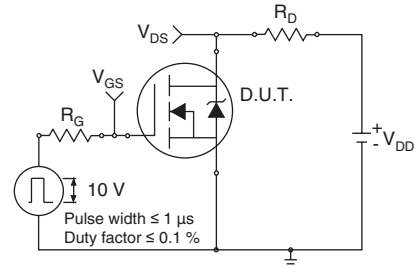


Fig. 10a - Switching Time Test Circuit

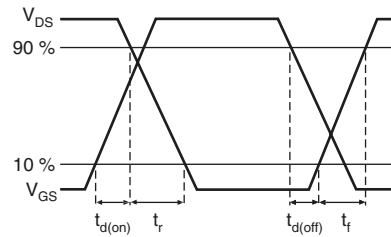


Fig. 10b - Switching Time Waveforms

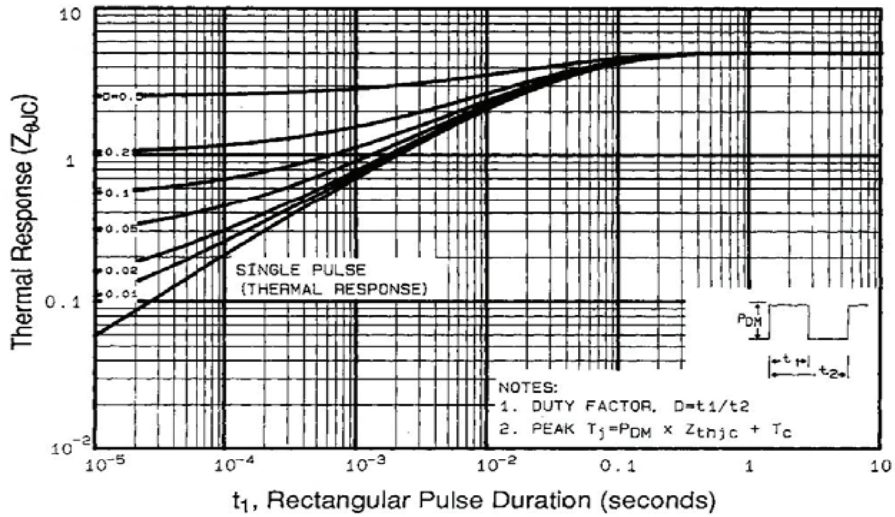


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

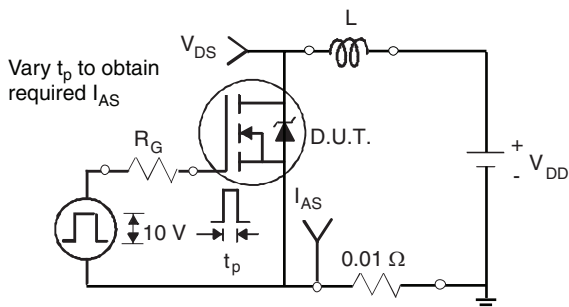


Fig. 12a - Unclamped Inductive Test Circuit

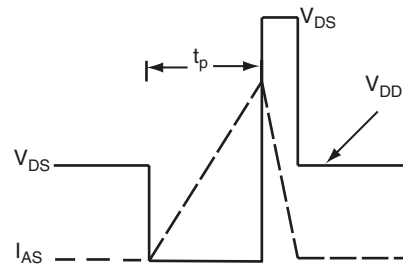


Fig. 12b - Unclamped Inductive Waveforms

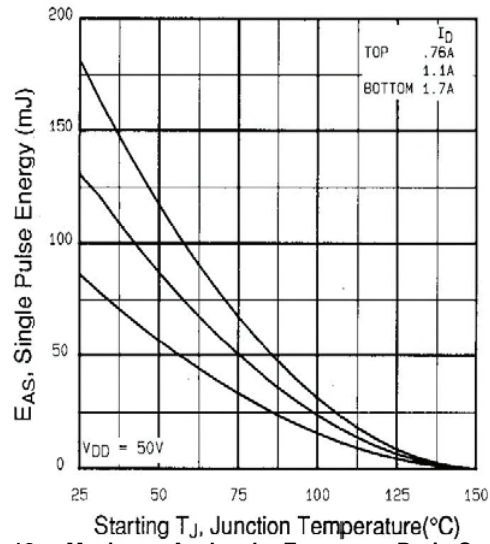


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

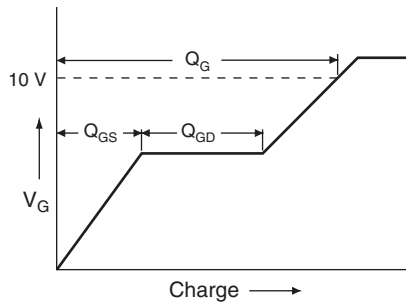


Fig. 13a - Basic Gate Charge Waveform

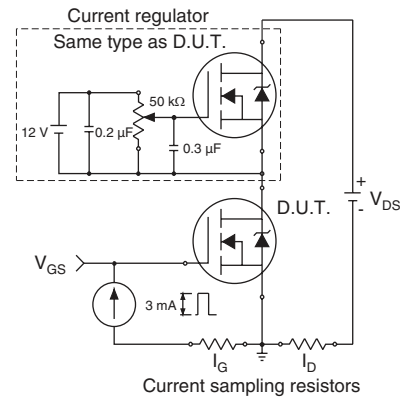
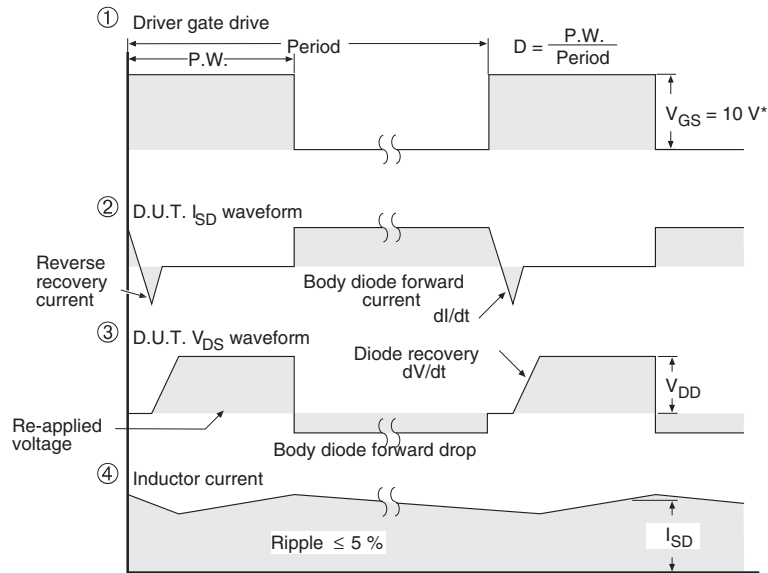
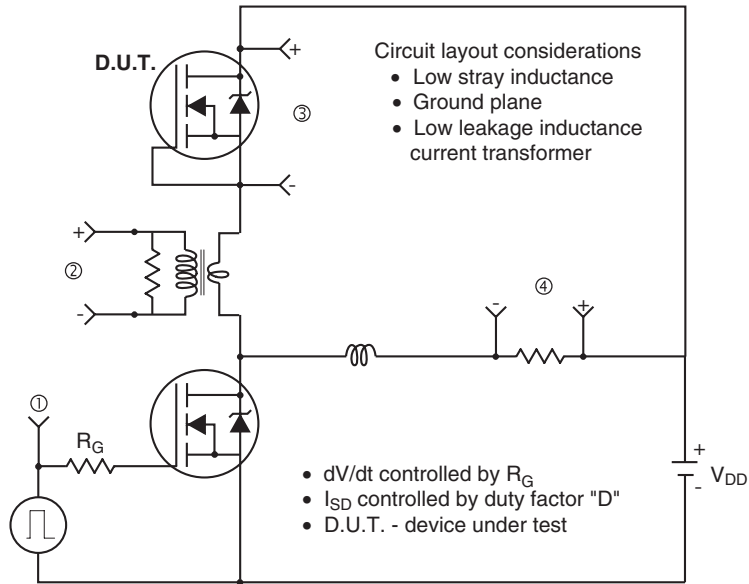


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5 V$ for logic level and $3 V$ drive devices

Fig. 14 - For N-Channel